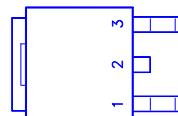
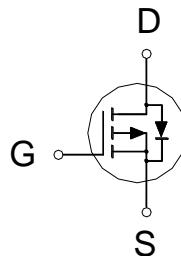


NIKO-SEM
**P-Channel Enhancement Mode
Field Effect Transistor**
P3506ED
TO-252
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-60V	35mΩ	-27A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-60	V
Gate-Source Voltage	V_{GS}	± 25	V
Continuous Drain Current ²	I_D	-27	A
		-17	
Pulsed Drain Current ¹	I_{DM}	-82	A
Avalanche Current	I_{AS}	-29	
Avalanche Energy	E_{AS}	42	mJ
Power Dissipation	P_D	50	W
		20	
Junction & Storage Temperature Range	T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	2.5	62.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1.3	-1.8	-2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 25V$			±100	nA

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Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -48V, V_{GS} = 0V$			-1	μA
		$V_{DS} = -40V, V_{GS} = 0V, T_J = 125^\circ C$			-10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = -4.5V, I_D = -15A$		41	55	$m\Omega$
		$V_{GS} = -10V, I_D = -20A$		30	35	
Forward Transconductance ¹	g_{fs}	$V_{DS} = -5V, I_D = -20A$		20		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -25V, f = 1MHz$		1432		pF
Output Capacitance	C_{oss}			149		
Reverse Transfer Capacitance	C_{rss}			101		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		3.7		Ω
Total Gate Charge ²	$Q_g (V_{GS}=-10V)$	$V_{DS} = -30V, V_{GS} = -10V, I_D = -20A$		29		nC
	$Q_g (V_{GS}=-4.5V)$			15		
Gate-Source Charge ²	Q_{gs}			4.3		
Gate-Drain Charge ²	Q_{gd}			8		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = -30V, I_D \approx -20A, V_{GS} = -10V, R_{GEN} = 6\Omega$		16		nS
Rise Time ²	t_r			67		
Turn-Off Delay Time ²	$t_{d(off)}$			55		
Fall Time ²	t_f			124		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_s				-27	A
Forward Voltage ¹	V_{SD}	$I_F = -20A, V_{GS} = 0V$			-1.3	V
Reverse Recovery Time	t_{rr}	$I_F = -20A, dI_F/dt = 100A/\mu S$		22		nS
Reverse Recovery Charge	Q_{rr}			18		nC

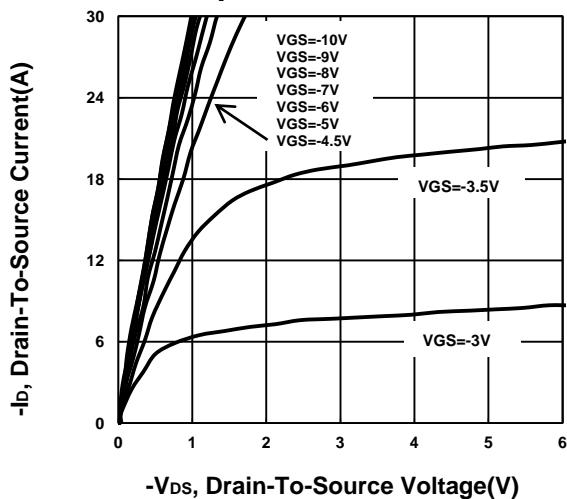
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature

NIKO-SEM

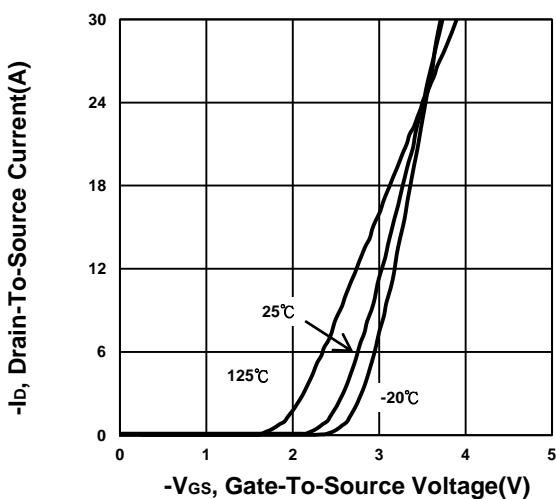
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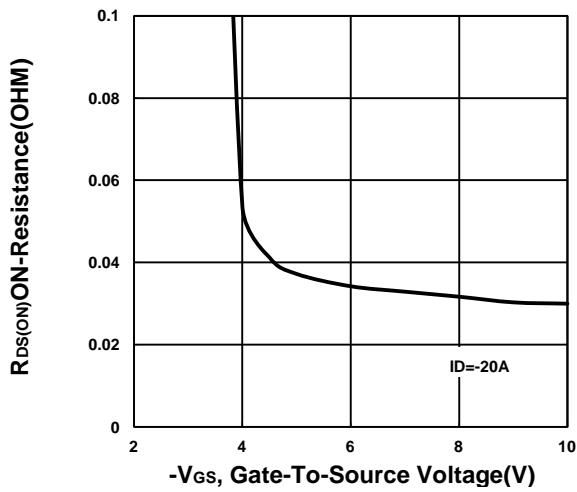
Output Characteristics



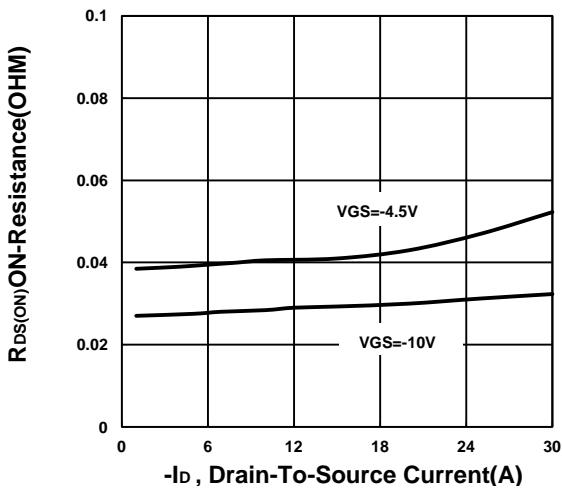
Transfer Characteristics



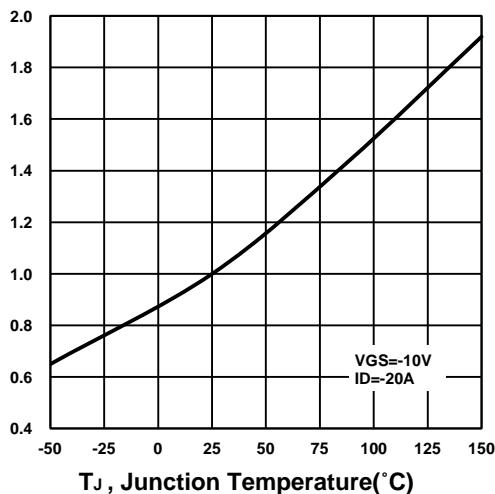
On-Resistance VS Gate-To-Source Voltage



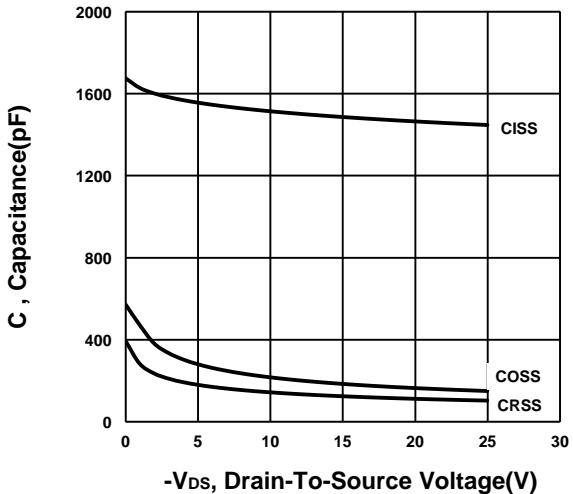
On-Resistance VS Drain Current



Normalized Drain to Source ON-Resistance



Capacitance Characteristic

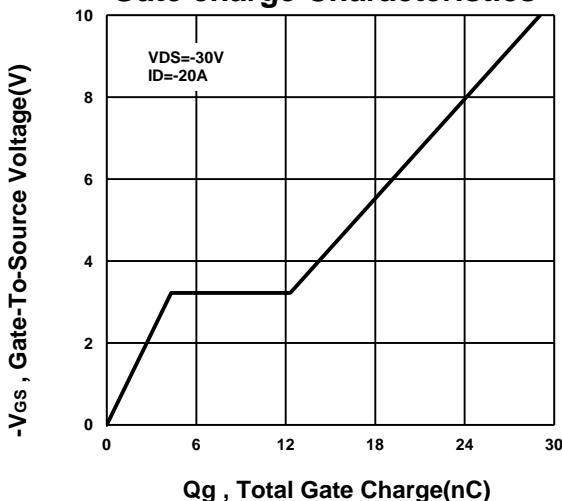


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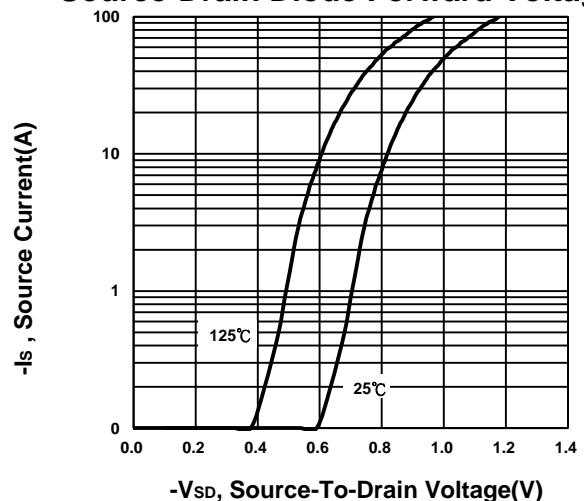
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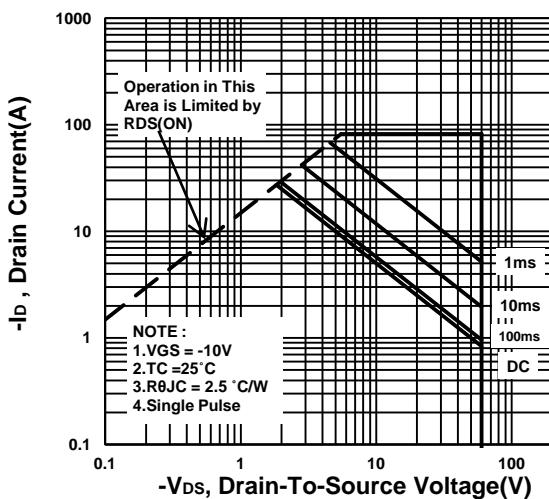
Gate charge Characteristics



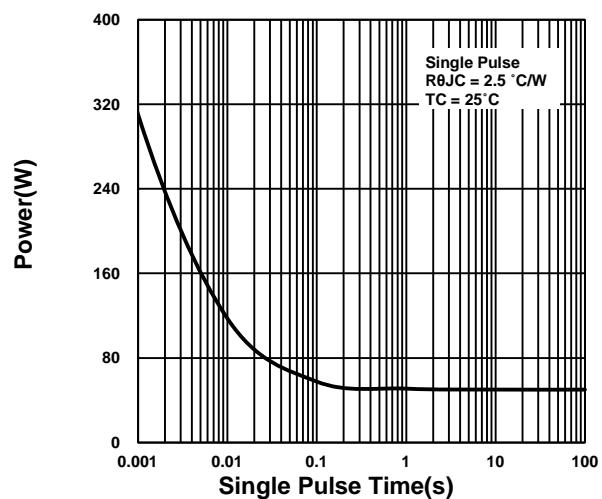
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

